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(12) **United States Design Patent**
Zhang et al.

(10) **Patent No.:** **US D740,142 S**

(45) **Date of Patent:** **** Oct. 6, 2015**

(54) **DIGITAL MICROMETER**

(56) **References Cited**

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(US)

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(**) Term: **14 Years**

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(21) Appl. No.: **29/494,973**

(57) **CLAIM**

The ornamental design for a digital micrometer, as shown and described.

(22) Filed: **Jun. 25, 2014**

DESCRIPTION

(51) **LOC (10) Cl.** **10-04**

FIG. 1 is a top, right perspective view of a digital micrometer showing our new design;
FIG. 2 is a top plan view thereof;
FIG. 3 is a left side view thereof;
FIG. 4 is a right side view thereof;
FIG. 5 is a bottom plan view thereof;
FIG. 6 is a head on view thereof; and,
FIG. 7 is a rear end view thereof.

(52) **U.S. Cl.**

USPC **D10/73**

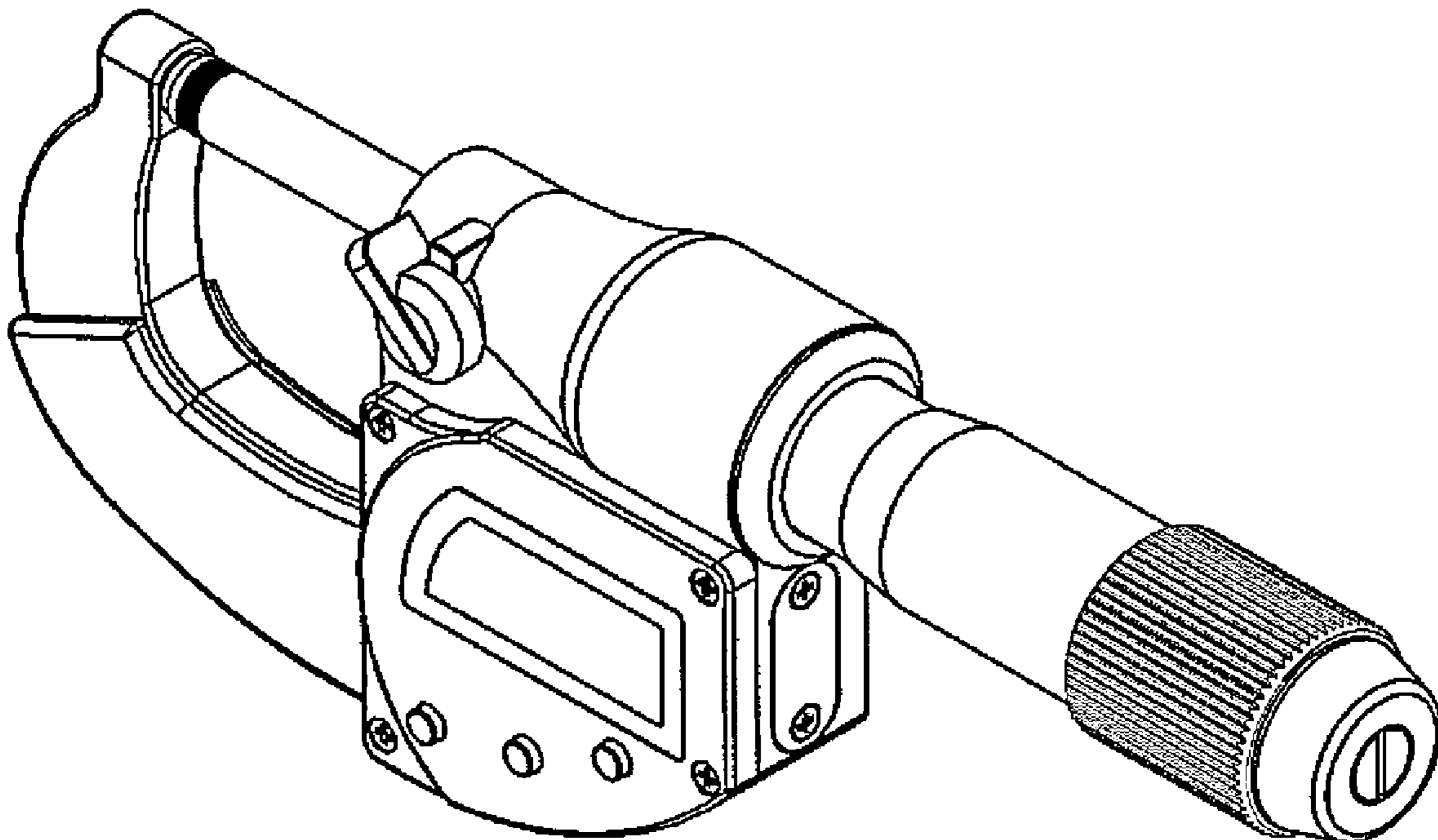
(58) **Field of Classification Search**

USPC D10/73

CPC G01B 3/20; G01B 3/205; G01B 5/24;
G01B 3/18; G01B 3/008

See application file for complete search history.

1 Claim, 4 Drawing Sheets



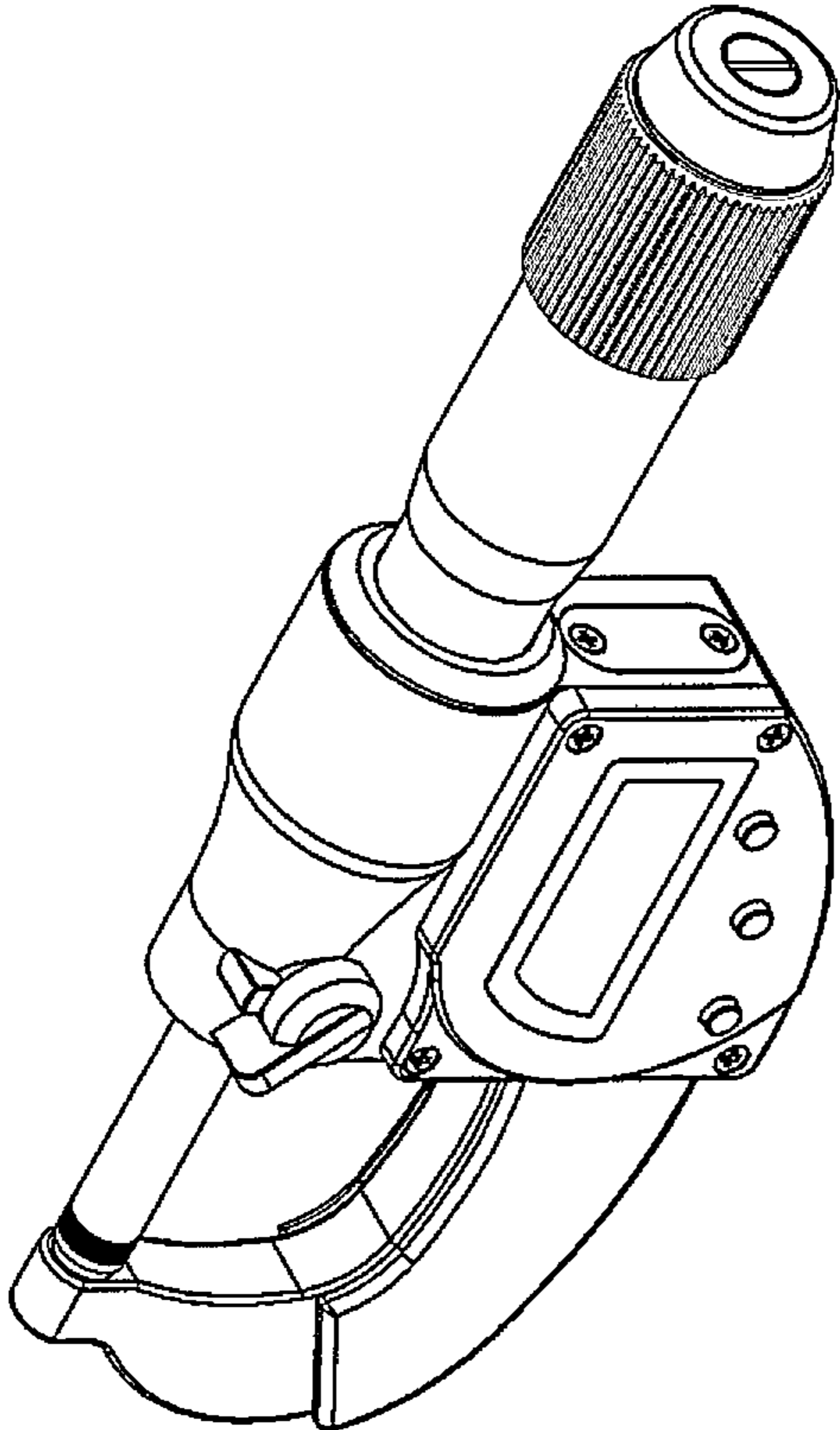


Fig. 1

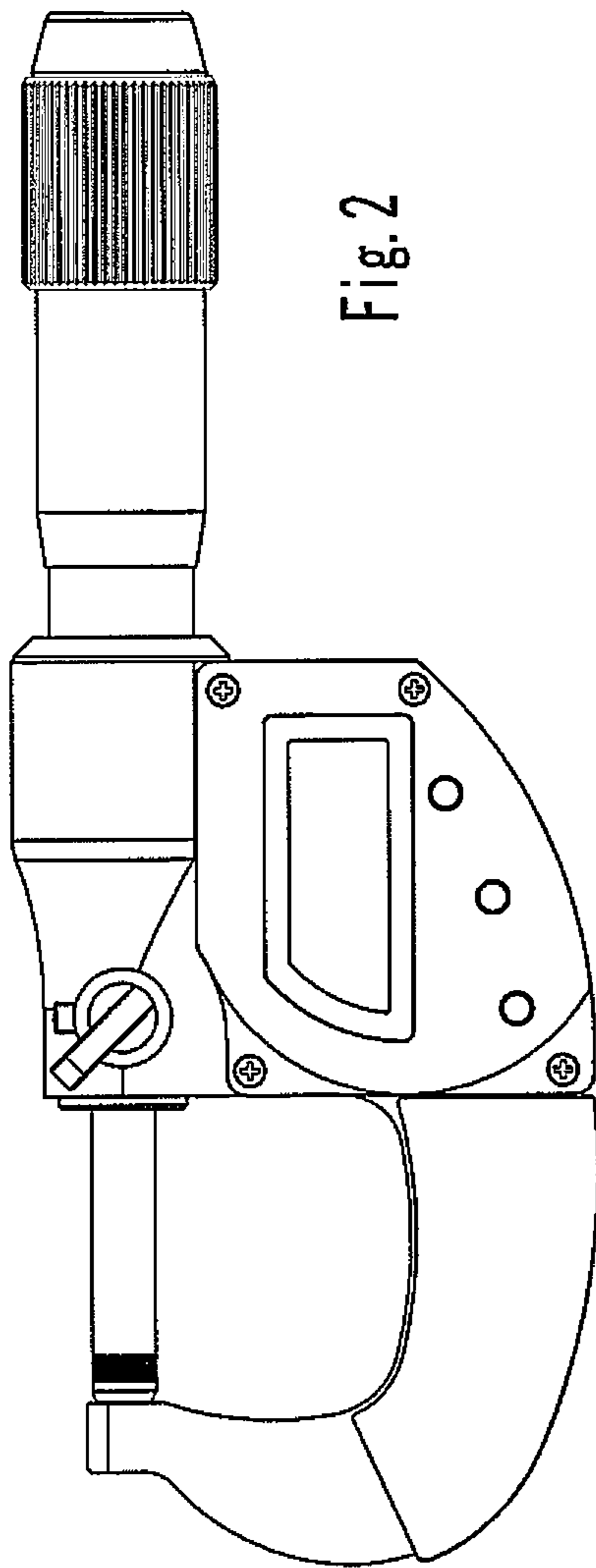


Fig. 2

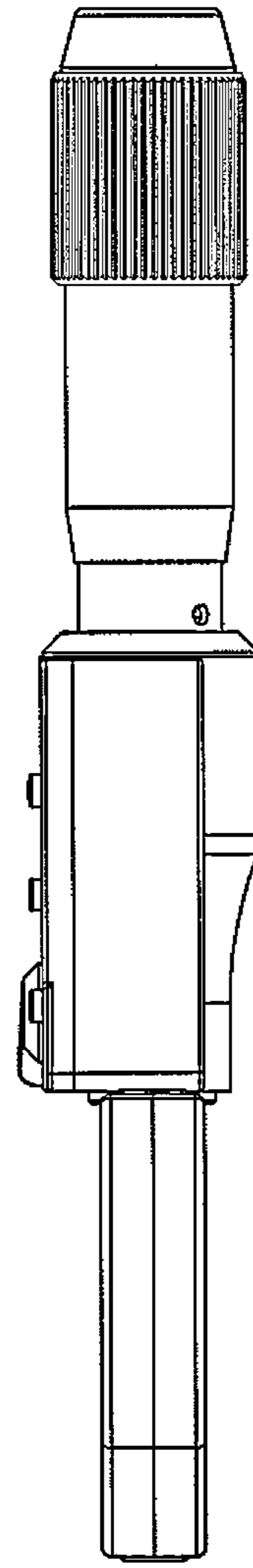


Fig. 3

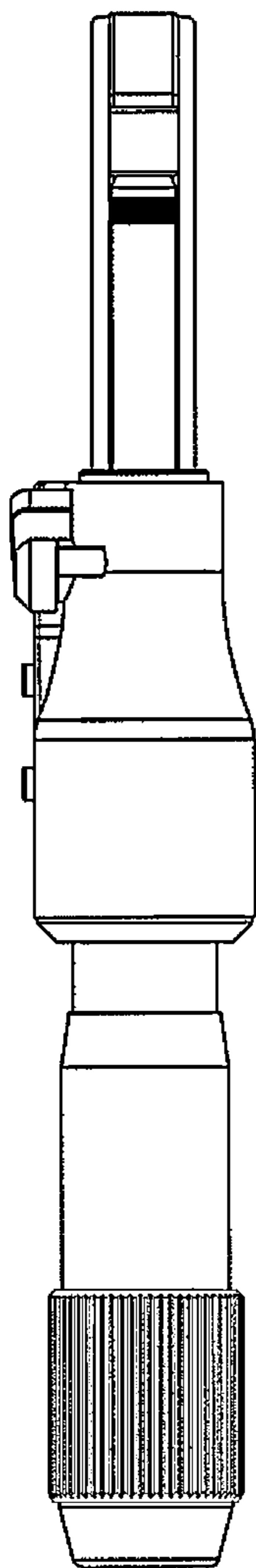


Fig. 4

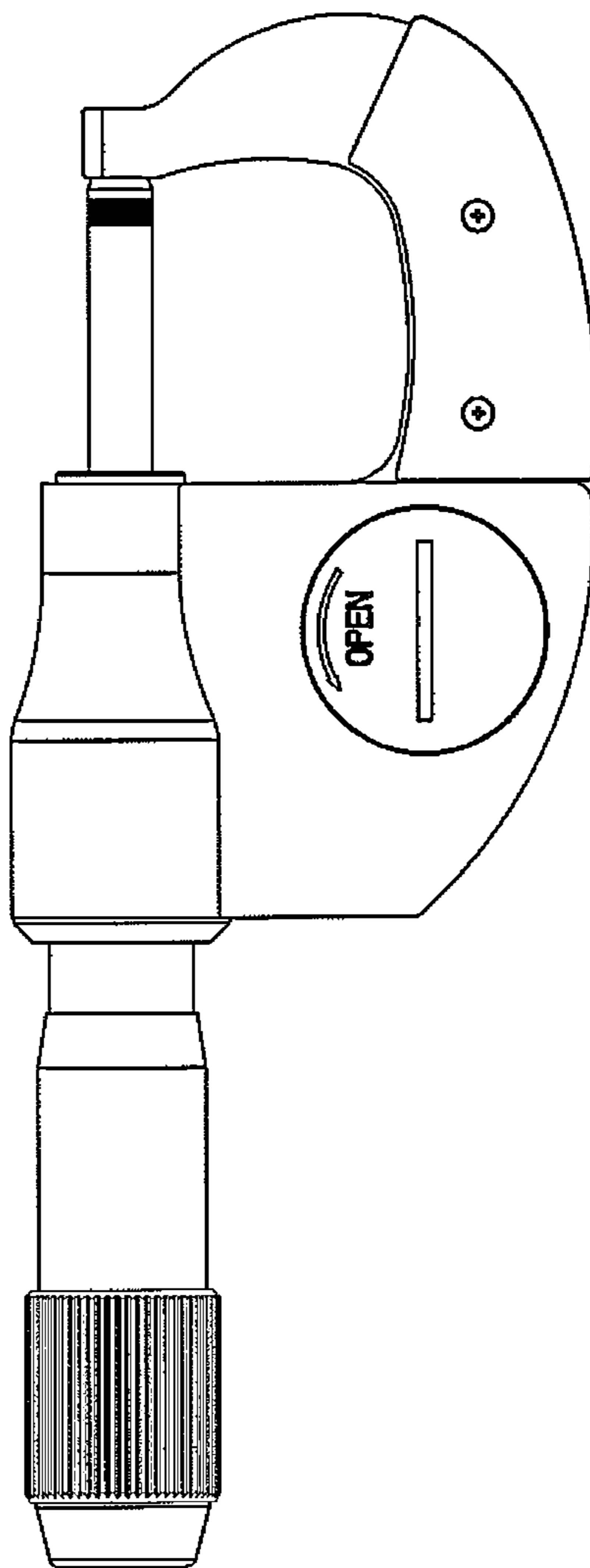


Fig. 5

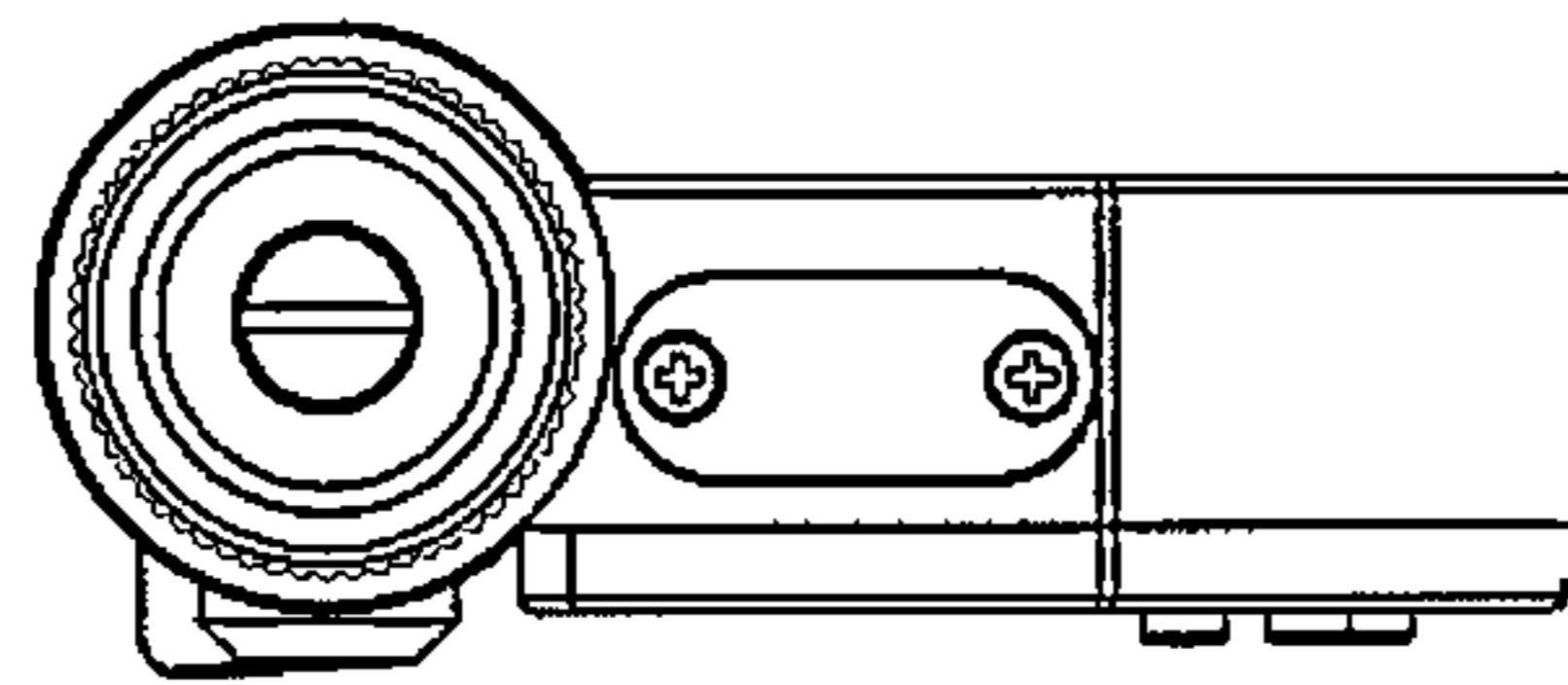


Fig. 7

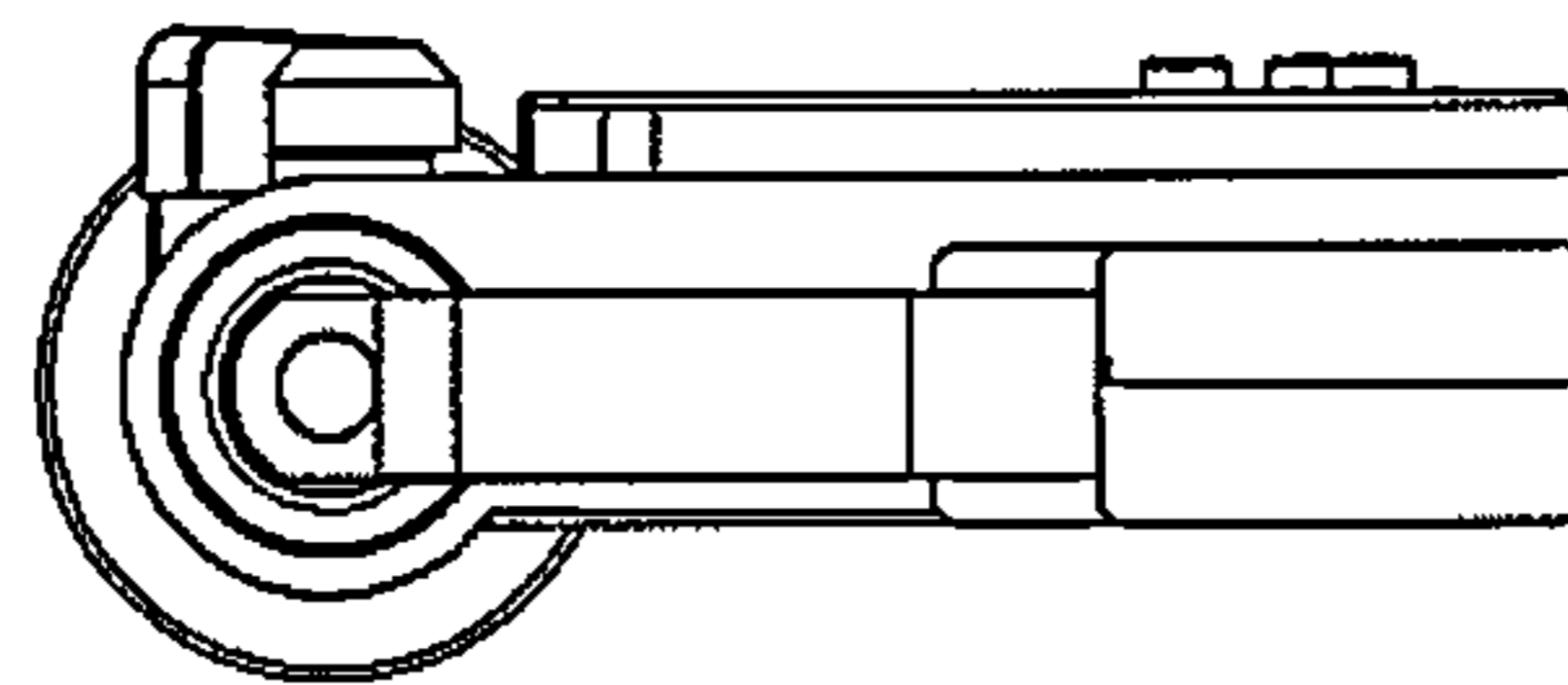


Fig. 6